



Securing the Edge

Guest Editor:

Prof. Dr. Akhilesh Tyagi

Department of Electrical and
Computer Engineering, Iowa
State University, Ames, IA 50011,
USA

Deadline for manuscript
submissions:

closed (20 December 2024)

Message from the Guest Editor

Recently, edge security has emerged as a challenge in the research community. SRC's "The Decadal Plan for Semiconductors" also highlights securing the edge as a challenge. Modern CPS systems have an edge computing component and a cloud-hosted server component. Depending on the applications and system architecture, a large volume of data flows through multiple sensing, aggregation, decision-making layers from the edge to the cloud, mostly through a variety of IoT devices.

Not only does the data need to be protected, the provenance can also play a key role in the overall system behavior correctness.

The decision-making AI is also being distributed to edge AI and the cloud-hosted large model AI. It is crucial to determine how the data affecting the fidelity of these AI decisions should be protected.

This Special Issue seeks papers on all aspects of edge security, including the following:

- IoT security;
- Data provenance;
- Edge network security;
- AI model security;
- Hardware assisted security techniques.





an Open Access Journal by MDPI

Editor-in-Chief

Prof. Dr. Giulio Nicola Cerullo
Dipartimento di Fisica,
Politecnico di Milano, Piazza L.
da Vinci 32, 20133 Milano, Italy

Message from the Editor-in-Chief

As the world of science becomes ever more specialized, researchers may lose themselves in the deep forest of the ever increasing number of subfields being created. This open access journal *Applied Sciences* has been started to link these subfields, so researchers can cut through the forest and see the surrounding, or quite distant fields and subfields to help develop his/her own research even further with the aid of this multi-dimensional network.

Author Benefits

Open Access: free for readers, with article processing charges (APC) paid by authors or their institutions.

High Visibility: indexed within Scopus, SCIE (Web of Science), Ei Compendex, Inspec, Embase, CAPlus / SciFinder, and other databases.

Journal Rank: JCR - Q2 (Engineering, Multidisciplinary) / CiteScore - Q1 (General Engineering)

Contact Us

Applied Sciences Editorial Office
MDPI, Grosspeteranlage 5
4052 Basel, Switzerland

Tel: +41 61 683 77 34
www.mdpi.com

mdpi.com/journal/applsci
applsci@mdpi.com
[X@Applsci](https://twitter.com/Applsci)